

# Henning Fouckhardt

## List of Publications by Year in descending order

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30  
papers

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citations

1040056

9  
h-index

1199594

12  
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docs citations

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times ranked

110  
citing authors

#	ARTICLE	IF	CITATIONS
1	Optoelectrowetting (OEW) with push-actuation of microdroplets at small frequencies and OEW equations revisited. <i>Sensors and Actuators A: Physical</i> , 2022, 334, 113331.	4.1	2
2	Lithography-Free Technology for the Preparation of Digital Microfluidic (DMF) Lab-Chips with Droplet Actuation by Optoelectrowetting (OEW). <i>International Journal of Analytical Chemistry</i> , 2022, 2022, 1-6.	1.0	4
3	Doped or Quantum-Dot Layers as In Situ Etch-Stop Indicators for III/V Semiconductor Reactive Ion Etching (RIE) Using Reflectance Anisotropy Spectroscopy (RAS). <i>Micromachines</i> , 2021, 12, 502.	2.9	6
4	Epitaxial Growth of Optoelectronically Active Ga(As)Sb Quantum Dots on Al-Rich AlGaAs with GaAs Capsule Layers. <i>Advances in Materials Science and Engineering</i> , 2021, 2021, 1-10.	1.8	0
5	Theory, simulation, fabrication, and characterization of Galois scattering plates for the optical and the THz spectral range. <i>AIP Advances</i> , 2021, 11, 065130.	1.3	0
6	High shape-accuracy of surface roughnesses upon nano-moulding with optical elastomers. <i>Optical Materials</i> , 2021, 118, 111230.	3.6	0
7	Interferometric in-situ III/V semiconductor dry-etch depth-control with $\hat{\Delta}\pm 0.8\hat{\Delta}\%$ nm best accuracy using a quadruple-Vernier-scale measurement. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , 2021, 39, 052204.	1.2	4
8	Microdroplet Actuation via Light Line Optoelectrowetting (LL-OEW). <i>International Journal of Analytical Chemistry</i> , 2021, 2021, 1-9.	1.0	4
9	1D Confocal Broad Area Semiconductor Lasers (Confocal BALs) for Fundamental Transverse Mode Selection (TMS#0). <i>Advances in OptoElectronics</i> , 2019, 2019, 1-7.	0.6	1
10	In-situ etch-depth control better than 5 nm with reflectance anisotropy spectroscopy (RAS) equipment during reactive ion etching (RIE): A technical RAS application. <i>AIP Advances</i> , 2019, 9, .	1.3	5
11	1 ML Wetting Layer upon Ga(As)Sb Quantum Dot (QD) Formation on GaAs Substrate Monitored with Reflectance Anisotropy Spectroscopy (RAS). <i>Advances in OptoElectronics</i> , 2018, 2018, 1-7.	0.6	1
12	Microfluidic Droplet Array as Optical Irises Actuated via Electrowetting. <i>Advances in OptoElectronics</i> , 2018, 2018, 1-8.	0.6	4
13	Atomic layer sensitive in-situ plasma etch depth control with reflectance anisotropy spectroscopy (RAS). , 2017, , .		1
14	Fundamental Transverse Mode Selection (TMS#0) of Broad Area Semiconductor Lasers with Integrated Twice-Retracted 4<i>f</i> Set-Up and Film-Waveguide Lens. <i>Advances in OptoElectronics</i> , 2017, 2017, 1-6. <a href="http://www.oee.org/1998/Math/MathML">Microfluidic Optical Stimulus Flexibly <math>\hat{\Delta}\text{mm}</math>mm=<math>\hat{\Delta}\text{http://www.oee.org/1998/Math/MathML</math></a>	0.6	1
15	$\hat{\Delta}\text{http://www.w3.org/1998/Math/MathML}$ id="M1"><math>x</math></math></math></math></math> Actuated via Electrowetting-on-Dielectrics with $\hat{\Delta}20\hat{\Delta}\%$ ms Response Time. <i>Advances in Optical Technologies</i> , 2017, 2017, 1-5.	0.8	0
16	Monolithically integrated fourier-optical transverse-mode selector for broad area lasers. , 2017, , .		0
17	Precise in situ etch depth control of multilayered III $\hat{\Delta}$ V semiconductor samples with reflectance anisotropy spectroscopy (RAS) equipment. <i>Beilstein Journal of Nanotechnology</i> , 2016, 7, 1783-1793.	2.8	9
18	Influence of plasma composition on reflectance anisotropy spectra for in situ III $\hat{\Delta}$ V semiconductor dry-etch monitoring. <i>Applied Surface Science</i> , 2015, 357, 530-538.	6.1	7

#	ARTICLE	IF	CITATIONS
19	Monitoring of (reactive) ion etching (RIE) with reflectance anisotropy spectroscopy (RAS) equipment. Applied Surface Science, 2015, 328, 120-124.	6.1	10
20	Combination of Transverse Mode Selection and Active Longitudinal Mode-Locking of Broad Area Semiconductor Lasers. Advances in OptoElectronics, 2014, 2014, 1-5.	0.6	0
21	GaSb quantum dots on GaAs with high localization energy of 710 meV and an emission wavelength of 1.3 $\mu\text{m}$ . Journal of Crystal Growth, 2014, 404, 48-53.	1.5	11
22	Generation of Dense Lying Ga(As)Sb Quantum Dots for Efficient Quantum Dot Lasers. Advanced Materials Research, 2013, 684, 285-289.	0.3	4
23	Ga(As)Sb/GaAs quantum dots for emission around 1300 nm. , 2013, , .		0
24	Dense lying self-organized GaAsSb quantum dots on GaAs for efficient lasers. Beilstein Journal of Nanotechnology, 2011, 2, 333-338.	2.8	10
25	Glass surface modification by lithography-free reactive ion etching in an Ar/CF <sub>4</sub> -plasma for controlled diffuse optical scattering. Surface and Coatings Technology, 2011, 205, S419-S424.	4.8	18
26	Multitude of glass surface roughness morphologies as a tool box for dosed optical scattering. Applied Optics, 2010, 49, 1364.	2.1	10
27	nm- and $\mu\text{m}$ -Scale Surface Roughness on Glass with Specific Optical Scattering Characteristics on Demand. Advances in OptoElectronics, 2007, 2007, 1-7.	0.6	16
28	Self-pulsation in broad area lasers with transverse-mode selective feedback. Optics Communications, 2006, 265, 642-648.	2.1	10
29	X-ray studies and time-resolved photoluminescence on optically pumped antimonide-based midinfrared type-II lasers. Spectrochimica Acta - Part A: Molecular and Biomolecular Spectroscopy, 2004, 60, 3387-3392.	3.9	1
30	An improved shooting approach for solving the time-independent Schrödinger equation for III/V QW structures. Physics Letters, Section A: General, Atomic and Solid State Physics, 2001, 286, 199-204.	2.1	16